EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	13	(window same mask$3 same pattern same match$3 same template$1)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/10/26 10:25
L2	2	1 and partial$3 near2 match$4	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/10/26 10:28
L3	130	partial$3 near2 template$1 same match$3	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/10/26 10:29
L4	23	3 and mask$3	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/10/26 10:30
L5	18	4 and pixel$1	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/10/26 10:30

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	149	window same mask$3 same pattern same match$3	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/10/26 10:51
L2	13	1 same template$1	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/10/26 10:55
L3	13	2 and match$3	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/10/26 11:06
L4	3465	partial$3 near match$3	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/10/26 11:07
L5	400	4 same (bit$1 or pixel$1)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/10/26 11:08
L6	156	5 same (mask$3 or template$1 or window$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/10/26 11:09
L7	60	6 same enhanc$4	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/10/26 11:10

L8	1	7 same (target or center or interest)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/10/26 11:10

IEEE *Xplore* ⁱᵖ
RELEASE 2.1

Welcome United States Patent and Trademark Office

☐ Search Results

BROWSE   **SEARCH**   **IEEE XPLORE GUIDE**

Results for "((partial* match* and template*)<in>metadata)"   ☑e-mail
Your search matched **8** of **1428539** documents.
A maximum of **100** results are displayed, **25** to a page, sorted by **Relevance** in **Descending** order.

» Search Options

View Session History

New Search

» Key

IEEE JNL	IEEE Journal or Magazine
IEE JNL	IEE Journal or Magazine
IEEE CNF	IEEE Conference Proceeding
IEE CNF	IEE Conference Proceeding
IEEE STD	IEEE Standard

Modify Search

((partial* match* and template*)<in>metadata)   **Search**

☐ Check to search only within this results set

Display Format: ◉ Citation   ○ Citation & Abstract

┌ **view selected items** ┐   **Select All Deselect All**

☐   1. **Performance optimization using template mapping for datapath-intensive synthesis**
Corazao, M.R.; Khalaf, M.A.; Guerra, L.M.; Potkonjak, M.; Rabaey, J.M.;
Computer-Aided Design of Integrated Circuits and Systems, IEEE Transaction:
Volume 15, Issue 8, Aug. 1996 Page(s):877 - 888
Digital Object Identifier 10.1109/43.511568

AbstractPlus | References | Full Text: PDF(1116 KB)   **IEEE JNL**
Rights and Permissions

☐   2. **Optical recognition of handwritten Chinese characters by partial matchin**
Wang, A.-B.; Huang, J.S.; Fan, J.-C.;
Document Analysis and Recognition, 1993., Proceedings of the Second Intern:
Conference on
20-22 Oct. 1993 Page(s):822 - 823
Digital Object Identifier 10.1109/ICDAR.1993.395611

AbstractPlus | Full Text: PDF(236 KB)   **IEEE CNF**
Rights and Permissions

☐   3. **Object matching on irregular pyramid**
Pailloncy, J.-G.; Kropatsch, W.; Jolion, J.-M.;
Pattern Recognition, 1998. Proceedings. Fourteenth International Conference ⁱ
Volume 2, 16-20 Aug. 1998 Page(s):1721 - 1723 vol.2
Digital Object Identifier 10.1109/ICPR.1998.712056

AbstractPlus | Full Text: PDF(36 KB)   **IEEE CNF**
Rights and Permissions

☐   4. **Surface signatures: an orientation independent free-form surface represe for the purpose of objects registration and matching**
Yamany, S.M.; Farag, A.A.;
Pattern Analysis and Machine Intelligence, IEEE Transactions on
Volume 24, Issue 8, Aug. 2002 Page(s):1105 - 1120
Digital Object Identifier 10.1109/TPAMI.2002.1023806

AbstractPlus | References | Full Text: PDF(6059 KB)   **IEEE JNL**
Rights and Permissions

☐   5. **Progressive coding of palette images and digital maps**
Forchhammer, S.; Salinas, J.M.;
Data Compression Conference, 2002. Proceedings. DCC 2002

2-4 April 2002 Page(s):362 - 371
Digital Object Identifier 10.1109/DCC.2002.999974

AbstractPlus | Full Text: PDF(389 KB)   IEEE CNF
Rights and Permissions

☐ 6. **Free-form surface registration using surface signatures**
Yamany, S.M.; Farag, A.A.;
Computer Vision, 1999. The Proceedings of the Seventh IEEE International Cc
Volume 2, 20-27 Sept. 1999 Page(s):1098 - 1104 vol.2
Digital Object Identifier 10.1109/ICCV.1999.790402

AbstractPlus | Full Text: PDF(372 KB)   IEEE CNF
Rights and Permissions

☐ 7. **Instruction set mapping for performance optimization**
Corazao, M.; Khalaf, M.; Guerra, L.; Potkonjak, M.; Rabaey, J.;
Computer-Aided Design, 1993. ICCAD-93. Digest of Technical Papers., 1993 I
International Conference on
7-11 Nov. 1993 Page(s):518 - 521
Digital Object Identifier 10.1109/ICCAD.1993.580107

AbstractPlus | Full Text: PDF(352 KB)   IEEE CNF
Rights and Permissions

☐ 8. **Photo time-stamp detection and recognition**
Xiangrong Chen; Hong-Jiang Zhang;
Document Analysis and Recognition, 2003. Proceedings. Seventh Internationa
3-6 Aug. 2003 Page(s):319 - 322 vol.1

AbstractPlus | Full Text: PDF(296 KB)   IEEE CNF
Rights and Permissions

Help   Contact Us   Privacy & :

Indexed by
☐ Inspec°

IEEE *Xplore* ™
RELEASE 2.1

Welcome United States Patent and Trademark Office

☐ **Search Session History**   **BROWSE**   **SEARCH**   **IEEE XPLORE GUIDE**

Edit an existing query or
compose a new query in the
Search Query Display.

Thu, 26 Oct 2006, 11:27:09 AM EST

Search Query Display

**Select a search number (#)
to:**

- Add a query to the Search
  Query Display
- Combine search queries
  using AND, OR, or NOT
- Delete a search
- Run a search

Recent Search Queries

#1   ((partial* match* and template*)<in>metadata)

#2   ((partial* match* and template*)<in>metadata)

#3   ((partial* match* and template*)<in>metadata)

#4   ((partial* match* and template*)<in>metadata)

#5   ((partial* match* and template*)<in>metadata)

Help   Contact Us   Privacy & :

Indexed by
Inspec

© Copyright 2006 IEEE –